

<i>Notice of References Cited</i>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/731,055	OVERSTREET, FRANK R.	
Examiner		Art Unit		Page 1 of 1
RICHARD M. BEMBEN		2622		

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,290,740	11-2007	Joy et al.	248/187.1
*	B US-7,128,297	10-2006	Lee, Eun-kyung	248/187.1
*	C US-7,422,379	09-2008	Agevik et al.	396/424
*	D US-2002/0107043	08-2002	Adamson et al.	455/550
*	E US-2003/0125075	07-2003	Klovborg, Flemming	455/556
*	F US-2004/0110544	06-2004	Oyagi et al.	455/575.1
*	G US-2004/0204056	10-2004	Phelps, William III	455/556.1
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2003319050 A	11-2003	Japan	YAMAMURA, KATSUHIRO	
O	JP 2004235964 A	08-2004	Japan	IGARI, KAZUO	
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.